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# **Overvoltage Protection Controllers** with Reverse Polarity Protection

# **General Description**

The MAX4864L/MAX4865L/MAX4866L/MAX4867 overvoltage protection controllers protect low-voltage systems against high-voltage faults up to +28V, and negative voltages down to -28V. These devices drive a low-cost complementary MOSFET. If the input voltage exceeds the overvoltage threshold, these devices turn off the n-channel MOSFET to prevent damage to the protected components. If the input voltage drops below ground, the devices turn off the p-channel MOSFET to prevent damage to the protected components. An internal charge pump eliminates the need for external capacitors and drives the MOSFET GATEN for a simple, robust solution.

The overvoltage thresholds are preset to +7.4V (MAX4864L), +6.35V (MAX4865L), +5.8V (MAX4866L), and +4.65V (MAX4867). When the input voltage drops below the undervoltage lockout (UVLO) threshold, the devices enter a low-current standby mode (8.5 $\mu$ A). Also in shutdown (EN set to logic-high), the current is reduced further (0.4 $\mu$ A). The MAX4864L/MAX4865L/MAX4866L have a +2.85V UVLO threshold, and the MAX4867 has a +2.5V UVLO threshold.

In addition, a ±15kV ESD protection is provided to the input when bypassed with a 1µF capacitor to ground. All devices are offered in a small 6-pin SOT23 and a 6-pin, 2mm x 2mm µDFN package, and are specified for operation over the -40°C to +85°C temperature range.

Applications

Cell Phones Digital Still Cameras PDAs and Palmtop Devices MP3 Players

### **Features**

- Overvoltage Protection Up to +28V
- Reverse Polarity Protection Down to -28V
- Preset Overvoltage (OV) Trip Level (7.4V, 6.35V, 5.8V, 4.65V)
- Drive Low-Cost Complementary MOSFET
- Internal 50ms Startup Delay
- Internal Charge Pump
- ♦ 8.5µA Standby Current (In UVLO Mode)
- ♦ 0.4µA Shutdown Current
- Overvoltage Fault FLAG Indicator
- 6-Pin (2mm x 2mm) µDFN and 6-Pin SOT23 Packages

### **\_Ordering Information**

PART	PIN- PACKAGE	OV TRIP LEVEL (V)	TOP MARK
MAX4864LEUT-T	6 SOT23-6	7.40	ABVO
MAX4864LELT	6 µDFN	7.40	AAE
MAX4865LEUT-T	6 SOT23-6	6.35	ABVP
MAX4865LELT	6 µDFN	6.35	AAF
MAX4866LEUT-T	6 SOT23-6	5.80	ABVQ
MAX4866LELT	6 µDFN	5.80	AAG
MAX4867EUT-T	6 SOT23-6	4.65	ABVN
MAX4867ELT	6 µDFN	4.65	AAD

**Note:** All devices are specified over the -40°C to +85°C operating temperature range.

T = Tape and reel.

Functional Diagram appears at end of data sheet.

#### ADAPTER (-28V TO +28V) Ν OUTPUT ▲ | ¥. 1uF GATEP IN GATEN //IXI//I MAX4864L MAX4865L MAX4866L MAX4867 EN GND FLAG

### M/IXI/M

\_ Maxim Integrated Products 1

For pricing, delivery, and ordering information, please contact Maxim Direct at 1-888-629-4642, or visit Maxim's website at www.maxim-ic.com.

### **Typical Operating Circuit**

### **ABSOLUTE MAXIMUM RATINGS**

IN to GND	0.3V to +30V
GATEN, GATEP to GND	0.3V to +12V
IN to GATEP	0.3V to +20V
FLAG, EN to GND	0.3V to +6V
Continuous Power Dissipation ( $T_A = +70^{\circ}C$ )	
6-Pin µDFN (2mm x 2mm) (derate 2.1mW/°C	
above +70°C)	
6-Pin SOT23 (derate 8.7mW/°C above +70°C)	696mW

Operating Temperature Range	40°C to +85°C
Junction Temperature	+150°C
Storage Temperature Range	65°C to +150°C
Lead Temperature (soldering, 10s)	+300°C
Soldering Temperature (reflow)	

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

### **ELECTRICAL CHARACTERISTICS**

 $(V_{IN} = +5V (MAX4864L/MAX4865L/MAX4866L), V_{IN} = +4V (MAX4867), T_A = -40^{\circ}C$  to  $+85^{\circ}C$ ,  $C_{GATEN} = 500$  pF, unless otherwise noted. Typical values are at T\_A = +25^{\circ}C.) (Note 1)

PARAMETER	SYMBOL	CONDITIONS			ТҮР	МАХ	UNITS	
Input Voltage Range	VIN			1.2		28.0	V	
0 H T H H			MAX4864L	7.0	7.4	7.8	- V	
	OVLO	V <sub>IN</sub> rising	MAX4865L	5.95	6.35	6.75		
Overvoltage Trip Level	OVLO		MAX4866L	5.45	5.8	6.15		
			MAX4867	4.35	4.65	4.95		
		MAX4864L			75		mV	
Overvoltage Lockout		MAX4865L			65			
Hysteresis		MAX4866L			55		IIIV	
		MAX4867			50		1	
Undervoltage Lockout	UVLO	V <sub>IN</sub> falling	MAX4864L/MAX4865L/MAX4866L	2.65	2.85	3.05		
Threshold	UVLO	VIN raining	MAX4867	2.3	2.5	2.7	2.7 V	
Undervoltage Lockout		MAX4864L/N	MAX4865L/MAX4866L		44		mV	
Hysteresis		MAX4867			25		mv	
IN Supply Current	lus i	$\overline{EN} = GND$	MAX4864L/MAX4865L/MAX4866L		77	120	μA	
	lin		MAX4867		68	110		
UVLO Supply Current	IUVLO	ĒN = GND	$\begin{array}{l} MAX4864L/MAX4865L/MAX4866L,\\ V_{IN}=+2.6V \end{array}$		8.5	22	μA	
			MAX4867, V <sub>IN</sub> = +2.2V		8	18		
Shutdown Supply Current	I <sub>SHD</sub>	<del>EN</del> = 1.6V	MAX4864L/MAX4865L/MAX4866L, V <sub>IN</sub> = 3.6V		0.4	2	μA	
			MAX4867, V <sub>IN</sub> = 3.6V		0.4	2		
			MAX4864L/MAX4865L/MAX4866L	9	9.83	10	v	
GATEN Voltage	VGATEN	1µA load	MAX4867	7.5	7.85	8.0	V	
GATEN Pulldown Current	IPD	$V_{IN} > OVLO, V_{GATEN} = +5.5V$		12	32	65	mA	
GATEP Clamp Voltage	VCLAMP			13.5	16.5	19.5	V	
GATEP Pulldown Resistor	RGATEP			32	48	64	kΩ	
FLAG Output-Low Voltage	VOL	ISINK = 1mA				0.4	V	
FLAG Leakage Current		$V_{FLAG} = +5.5V$				1	μA	
EN Input-High Voltage	VIH			1.5			V	
EN Input-Low Voltage	VIL					0.4	V	



# **ELECTRICAL CHARACTERISTICS (continued)**

(V<sub>IN</sub> = +5V (MAX4864L/MAX4865L/MAX4866L), V<sub>IN</sub> = +4V (MAX4867), T<sub>A</sub> = -40°C to +85°C, C<sub>GATEN</sub> = 500pF, unless otherwise noted. Typical values are at T<sub>A</sub> = +25°C.) (Note 1)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
EN Input Leakage Current	I <sub>LKG</sub>	$\overline{\text{EN}}$ = GND or +5.5V			1	μA
TIMING						
Startup Delay	<b>t</b> START	$V_{IN}$ > UVLO to $V_{GATEN}$ > 0.3V, Figure 1	20	50	80	ms
FLAG Blanking Time	<b>t</b> BLANK	V <sub>GATEN</sub> > 0.3V to V <sub>FLAG</sub> < 0.3V, Figure 1	20	50	80	ms
GATEN Turn-On Time	tgon	C <sub>GATEN</sub> = 500pF, V <sub>GATEN</sub> = 0.3V to +8V (MAX4864L/MAX4865L/MAX4866L) V <sub>GATEN</sub> = 0.3V to +7V (MAX4867), Figure 1		10		ms
GATEN Turn-Off Time	tgoff	V <sub>IN</sub> rising at 3V/µs from +5V to +8V (MAX4864L/MAX4865L/MAX4866L), or from +4V to +7V (MAX4867) V <sub>GATEN</sub> = 0.3V, C <sub>GATEN</sub> = 500pF, Figure 2		7	20	μs
FLAG Assertion Delay	tflag	V <sub>IN</sub> rising at 3V/µs from 5V to 8V (MAX4864L/MAX4865L/MAX4866L), or from +4V to +7V (MAX4867), V <sub>FLAG</sub> = 0.3V, Figure 2		3.5		μs
Initial Overvoltage Fault Delay	tovp	V <sub>IN</sub> rising at 3V/µs from 0V to +9V, time from V <sub>IN</sub> = 5V to I <sub>GATEN</sub> = 80% of I <sub>PD</sub> (GATEN pulldown current), Figure 3		1.5		μs
Disable Time	tDIS	$V_{\overline{EN}}$ = +2.4V, $V_{GATEN}$ = 0.3V, Figure 4		2		μs

Note 1: All parts are 100% tested at +25°C. Electrical limits across the full temperature range are guaranteed by design and correlation.

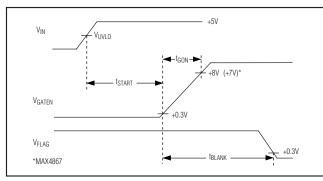


Figure 1. Startup Timing Diagram

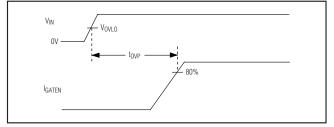


Figure 3. Power-Up Overvoltage Timing Diagram

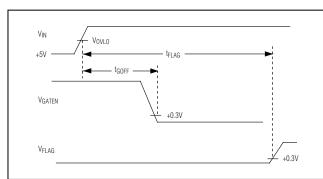


Figure 2. Shutdown Timing Diagram

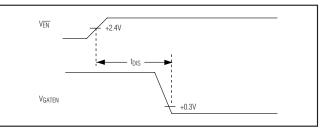
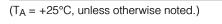
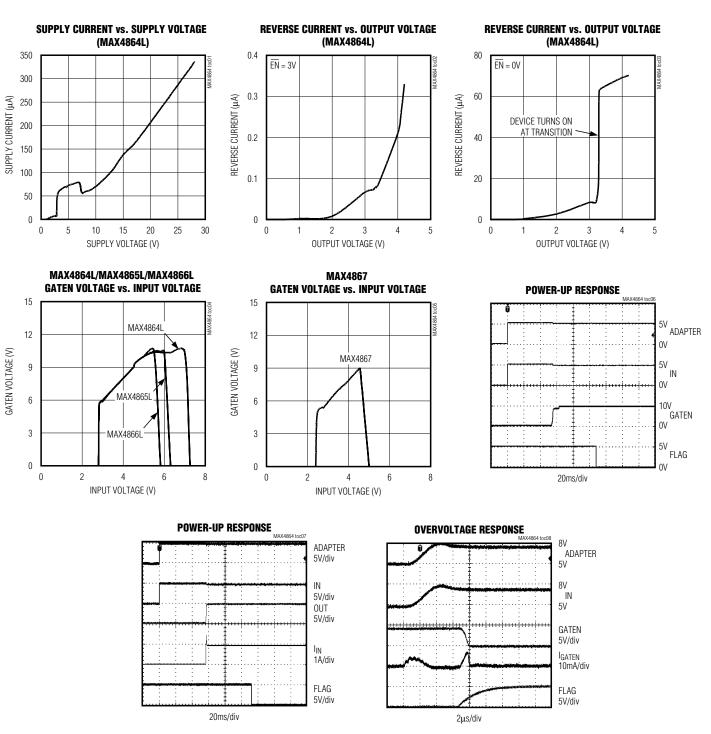


Figure 4. Disable Timing Diagram



# **Typical Operating Characteristics**

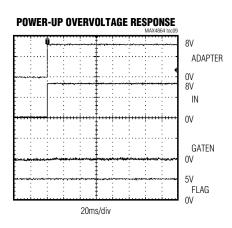
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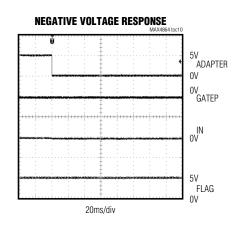


MAX4864L/MAX4865L/MAX4866L/MAX4867

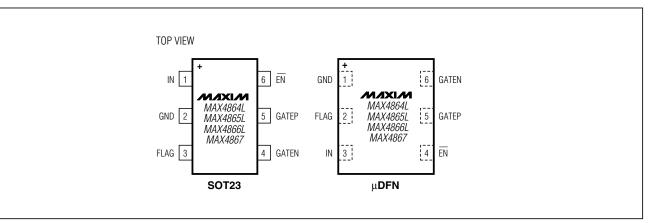
# Typical Operating Characteristics (continued)

 $(T_A = +25^{\circ}C, unless otherwise noted.)$ 





### Pin Configuration



### Pin Description

PI	N				
MAX4864LEUT/ MAX4865LEUT/ MAX4866LEUT/ MAX4867EUT	MAX4864LELT/ MAX4865LELT/ MAX4866LELT/ MAX4867ELT	NAME	FUNCTION		
1	3	IN	Voltage Input. IN is both the power-supply input and the overvoltage sense input.		
2	1	GND	Ground		
3	2	FLAG	Fault-Indication Output. When EN goes high, FLAG becomes high-impedance. FLAG is asserted high during undervoltage lockout and overvoltage lockout conditions. FLAG is deasserted during normal operation. FLAG is an open-drain output.		
4	6	GATEN	n-Channel MOSFET Gate-Drive Output. GATEN is the output of an on-chip charge pump. When $V_{UVLO} < V_{IN} < V_{OVLO}$ , GATEN is driven high to turn on the external n-channel MOSFET.		
5	5	GATEP	p-Channel MOSFET Gate-Drive Output. GATEP is always on when input is above ground and off when input drops below ground.		
6	4	ĒN	Active-Low Enable Input. Connect to ground in normal operation. Drive $\overline{\text{EN}}$ high to disable device and enter shutdown mode.		

## **Detailed Description**

The MAX4864L/MAX4865L/MAX4866L/MAX4867 provide up to +28V overvoltage and negative voltage protection for low voltage systems. When the input voltage exceeds the overvoltage trip level, the MAX4864L/MAX4865L/ MAX4866L/MAX4867 turn off a low-cost external n-channel MOSFET to prevent damage to the protected components. The devices also drive an external p-channel MOSFET to protect against negative voltage inputs. An internal charge-pump (see the *Functional Diagram*), drives the MOSFET GATEN for a simple, robust solution. On power-up, the device waits for 50ms before driving GATEN high. The open-drain FLAG output is kept at a high impedance for an additional 50ms after GATEN goes high before deasserting. The FLAG output asserts high immediately to an overvoltage fault.

#### **Undervoltage Lockout (UVLO)**

The MAX4864L/MAX4865L/MAX4866L have a fixed +2.85V typical UVLO level, and the MAX4867 has +2.5V UVLO level. When  $V_{\rm IN}$  is less than the UVLO, the GATEN driver is held low and FLAG is asserted.

#### **Overvoltage Lockout (OVLO)**

The MAX4864L has a +7.4V typical OVLO threshold; the MAX4865L has +6.35V typical OVLO threshold; the MAX4866L has a +5.8V typical OVLO threshold; and the MAX4867 has a +4.65V typical OVLO threshold. When V<sub>IN</sub> is greater than OVLO, the GATEN driver is held low and FLAG is asserted.

**FLAG Output** The open-drain FLAG output is used to signal to the host system when there is a fault with the input voltage. On power-up, FLAG is held high for 50ms after GATEN turns on, before deasserting. FLAG asserts immediately to overvoltage and undervoltage faults. When the fault condition is removed, FLAG deasserts 50ms after GATEN turns on. Connect a pullup resistor from FLAG to the logic I/O voltage of the host system.

#### **GATEN Driver**

An on-chip charge pump is used to drive GATEN above IN, allowing the use of a low-cost n-channel MOSFET. The charge pump operates from the internal +5.5V regulator.

The actual GATEN output voltage tracks approximately two times V<sub>IN</sub> until V<sub>IN</sub> exceeds +5.5V, or the OVLO trip level is exceeded, whichever comes first. The MAX4864L has a +7.4V typical OVLO, therefore GATEN remains relatively constant at approximately +10.5V for +5.5V < V<sub>IN</sub> < +7.4V. The MAX4866L has a +5.8V typical OVLO, but this can be as low as +5.5V. The GATEN

output voltage is a function of input voltage, as shown in the *Typical Operating Characteristics*.

#### **GATEP** Driver

When the input voltage drops below ground, GATEP goes high turning the external p-channel MOSFET off. When the input voltage goes above ground, GATEP pulls low and turns on the p-channel MOSFET. An internal clamp protects the p-channel MOSFET by insuring that the GATEP-to-IN voltage does not exceed +16V when the input (IN) rises to +28V.

#### **Device Operation**

The MAX4864L/MAX4865L/MAX4866L/MAX4867 have an on-board state machine to control device operation. A flowchart is shown in Figure 5. On initial power-up, if  $V_{IN} < UVLO$  or if  $V_{IN} > OVLO$ , GATEN is held at 0V and FLAG is high.

If UVLO < V<sub>IN</sub> < OVLO, the device enters startup after a 50ms internal delay. The internal charge pump is enabled, and GATEN begins to be driven above V<sub>IN</sub> by the internal charge pump. FLAG is held high during startup until the FLAG blanking period expires, typically 50ms after the GATEN starts going high. At this point, the device is in its on-state.

At any time if  $V_{\text{IN}}$  drops below UVLO, FLAG is driven high and GATEN is driven to ground.

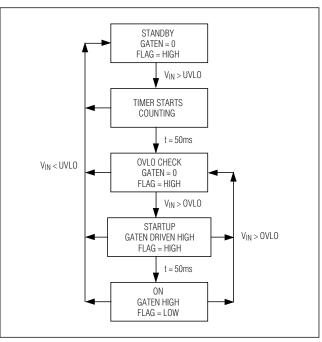


Figure 5. State Diagram

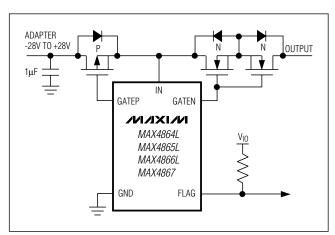


Figure 6. Back-to-Back External MOSFET Configuration

### **Applications Information**

#### **MOSFET Configuration**

The MAX4864L/MAX4865L/MAX4866L/MAX4867 can be used with either a complementary MOSFET configuration as shown in the *Typical Operating Circuit*, or can be configured with a single p-channel MOSFET and back-to-back n-channel MOSFETs as shown in Figure 6.

The MAX4864L/MAX4865L/MAX4866L/MAX4867 can drive either a complementary MOSFET or a single p-channel MOSFET and back-to-back n-channel MOSFETs. The back-to-back configuration has almost zero reverse current when the adapter is not present or when the adapter voltage is below the UVLO threshold.

If reverse current leakage is not a concern, a single MOSFET can be used. This approach has half the loss of the back-to-back configuration when used with similar MOSFET types and is a lower cost solution. Note that if the input is actually pulled low, the output will also be pulled low due to the parasitic body diode in the MOSFET. If this is a concern, then the back-to-back configuration should be used.

#### **MOSFET Selection**

The MAX4864L/MAX4865L/MAX4866L/MAX4867 are designed for use with a complementary MOSFET or single p-channel and dual back-to-back n-channel MOSFETs. In most situations, MOSFETs with R<sub>ON</sub> specified for a V<sub>GS</sub> of 4.5V work well. Also the V<sub>DS</sub> should be +30V for the MOSFET to withstand the full +28V IN range of the MAX4864L/MAX4865L/MAX4866L/ MAX4867. Table 1 shows a selection of MOSFETs which are appropriate for use with the MAX4864L/MAX4865L/MAX4866L/MAX4865L/MAX4866L/MAX4867.

#### **IN Bypass Considerations**

For most applications, bypass ADAPTER to GND with a  $1\mu$ F ceramic capacitor. If the power source has significant inductance due to long lead length, take care to prevent overshoots due to the LC tank circuit and provide protection if necessary to prevent exceeding the +30V absolute maximum rating on IN.

#### **ESD** Test Conditions

ESD performance depends on a number of conditions. The MAX4864L/MAX4865L/MAX4866L/MAX4867 are specified for  $\pm 15$ kV typical ESD resistance on IN when ADAPTER is bypassed to ground with a 1µF ceramic capacitor.

#### Human Body Model

Figure 7 shows the Human Body Model, and Figure 8 shows the current waveform it generates when discharged into a low impedance. This model consists of a 100pF capacitor charged to the ESD voltage of interest, which is then discharged into the device through a  $1.5 \mathrm{k}\Omega$  resistor.

PART	CONFIGURATION/ PACKAGE	V <sub>GS</sub> MAX (V)	V <sub>DS</sub> MAX (V)	R <sub>ON</sub> AT 4.5V (mΩ)	MANUFACTURER
Si5504DC	Complementary	±20	+30	143 (n-MOSFET)	
315504DC	MOSFET/1206-8	±20	-30	290 (p-MOSFET)	
Si5902DC	Dual/1206-8	±20	+30	143 (n-MOSFET)	Vishay Siliconix
Si1426DH	Single/µDFN-6	±20	+30	115 (n-MOSFET)	
Si5435DC	Single/1206-8	±20	-30	80 (p-MOSFET)	
FDC6561AN	Dual/SSOT-6	±20	+30	145 (n-MOSFET)	
FDG315N	Single/µDFN-6	±20	+30	160 (n-MOSFET)	Fairchild Semiconductor
FDC658P	Single/SSOT-6	±20	-30	75 (p-MOSFET)	Fairchild Semiconductor
FDC654P	Single/SSOT-6	±20	-30	125 (p-MOSFET)	

#### Table 1. MOSFET Suggestions



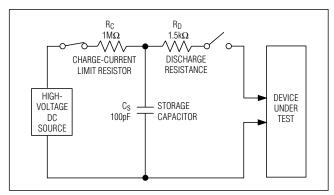


Figure 7. Human Body ESD Test Model

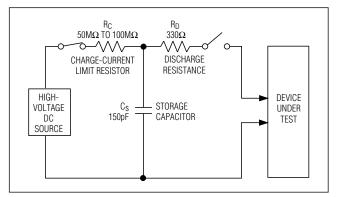


Figure 9. IEC 1000-4-2 ESD Test Model

#### IEC 1000-4-2

Since January 1996, all equipment manufactured and/or sold in the European Union has been required to meet the stringent IEC 1000-4-2 specification. The IEC 1000-4-2 standard covers ESD testing and performance of finished equipment. It does not specifically refer to ICs. The MAX4864L/MAX4865L/MAX4866L/ MAX4867 help users design equipment that meets Level 3 of IEC 1000-4-2, without additional ESD-protection components.

The main difference between tests done using the Human Body Model and IEC 1000-4-2 is higher peak current in IEC 1000-4-2. Because series resistance is lower in the IEC 1000-4-2 ESD test model (Figure 9), the ESD-withstand voltage measured to this standard is gen-

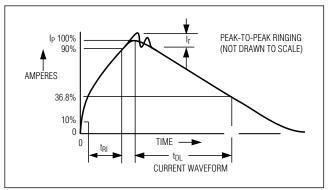


Figure 8. Human Body Current Waveform

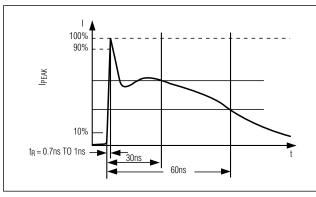


Figure 10. IEC 1000-4-2 ESD Generator Current Waveform

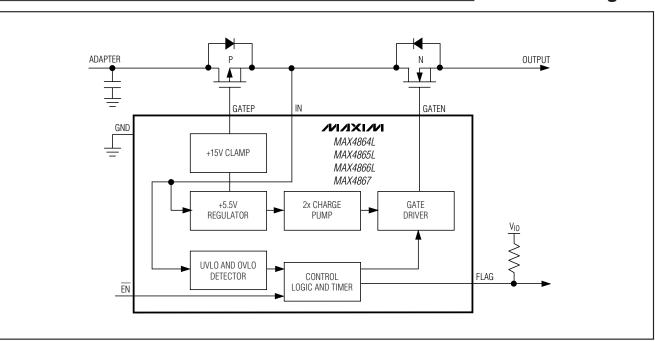
erally lower than that measured using the Human Body Model. Figure 10 shows the current waveform for the  $\pm$ 8kV IEC 1000-4-2 Level 4 ESD Contact Discharge test. The Air-Gap test involves approaching the device with a charger probe. The Contact Discharge method connects the probe to the device before the probe is energized.

PROCESS: BICMOS



**MAX4864L/MAX4865L/MAX4866L/MAX4867** 

\_Functional Diagram



### **Package Information**

For the latest package outline information and land patterns, go to <u>www.maxim-ic.com/packages</u>. Note that a "+", "#", or "-" in the package code indicates RoHS status only. Package drawings may show a different suffix character, but the drawing pertains to the package regardless of RoHS status.

PACKAGE TYPE	PACKAGE CODE	DOCUMENT NO.
6 µDFN	L622-1	<u>21-0164</u>
6 SOT23	U6-1	<u>21-0058</u>

### **Revision History**

REVISION	REVISION	DESCRIPTION	PAGES
NUMBER	DATE		CHANGED
2	5/10	Deleted package codes from the <i>Ordering Information</i> table; updated the <i>Pin Configuration</i> , Figure 7, and Figure 9; deleted the transistor count from the <i>Chip Information</i> section	1, 6, 9, 10

Maxim cannot assume responsibility for use of any circuitry other than circuitry entirely embodied in a Maxim product. No circuit patent licenses are implied. Maxim reserves the right to change the circuitry and specifications without notice at any time.

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\_\_\_\_ 11